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5	Substitute fo	or form 1449A/PTC	)		Complete if Known			
					Application Number	Not Known 10/705294		
	INFOF	RMATION D	DISC	LOSURE	Filing Date	11/10/2003		
	STAT	EMENT BY	'AP	PLICANT	First Named Inventor	Silver et al.		
					Group Art Unit	2625		
	. (u.	se as many sheets	as ne	cessary)	Examiner Name	D. Mariam		
9	Sheet	1	of	3	Attorney Docket Number	C97-050 CON3		

_				U.S. PATENT DOCUMEN	TS	
Examiner Initials	Cite No.'	U.S. Patent Doo	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Cits / Support
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Examiner	Cite No. <sup>1</sup>	Foreign Patent Document		Name of Patentee or Applicant of	Date of Publication of	Pages, Columns, Lines,	Τ.		
Initials*		Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)	Cited Document	Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear		
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Signature Considered 3 1+ 6 0	1 71171 (41)	

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Substit	ute for form 1449E	B/PTO		Complete if Known		
				Application Number	Not Known (0/705294	
INF	ORMATIO	N DI	SCLOSURE	Filing Date	11/10/2003	
STA	ATEMENT	BY A	PPLICANT	First Named Inventor	Silver, et al.	
				Group Art Unit	2621	
	(use as many sl	heets as	necessary)	Examiner Name	D. Mariam	
Sheet	2 .	of	3	Attorney Docket Number	C97-050 CON3	

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>			
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Examiner Signature	M	Date Considered	3/17/06
Digitature	IIV.	Considered	

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Substite	ute for form 144	9B/PTO		Complete if Known			
				Application Number	Not Known 10/705294		
INF	ORMAŢIC	ON DIS	CLOSURE	Filing Date	11/10/2003		
STA	ATEMENT	BY AF	PPLICANT	First Named Inventor	Silver et al.		
				Group Art Unit	2625		
	(use as many	sheets as n	ecessary)	Examiner Name	D. Mariam		
Sheet	3	of	3	Attorney Docket Number	C97-050_CON3		

OTHER PRIOR	R ART -	NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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Signature		Considered 3-17-06	

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup>Unique citation designation number. <sup>2</sup>Applicant is to place a check mark here if English language Translation is attached.